



# Test Textured and Non-Textured Glass

## TMS-2000UV-RC

**Radial and  
Circumferential  
surface  
measurements  
with Texture  
Levels and Ratio  
reporting**

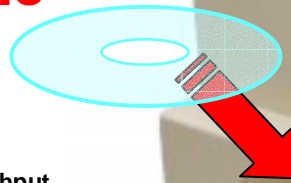
### Benefits:

- Quadruple Production Throughput
- Measure Radial, Circumferential
- Unaffected by environmental conditions
- Minimal operator training required
- Lowest cost per measurement of any system
- Stable – Easy to use
- Correlates to other measurement instruments via slope/offset.

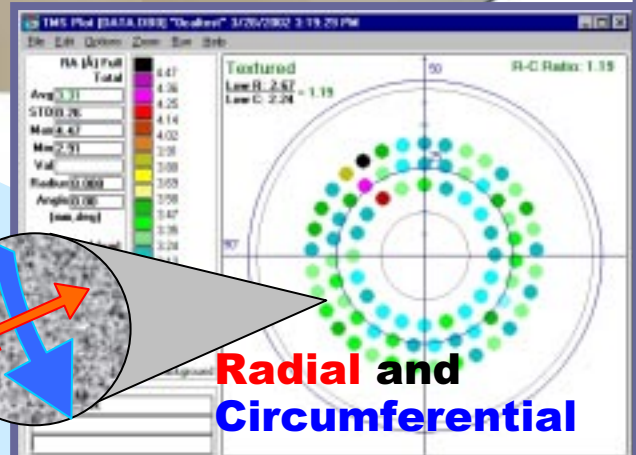
### Features:

- Non-Contact Measurements cannot harm test surfaces
- Results – RA, RMS roughness from 1Å up to 500Å
- Cost – Lower costs than Profilometer, AFM or Interferometers
- Precision – Resolution of 0.01Å reproducibility +/-0.25Å or 1% and repeatability: +/-0.2 Å
- Speed – Typically 50 test points in 60 sec.

**Quick and Easy**



Patent's 5,625,451 and 5,661,556 – other Patents Pending



# The Ultimate In Microroughness Measurements

The fastest, highest resolution, most stable non-contact microroughness measurement system in the world. Advanced light scatter technology packaged into a system ideally suited for qualifying and quantifying full surface textures and zone microroughness testing. Discover the

ultimate answer to fast, reliable microroughness measurements in glass/ceramic disk manufacturing, with systems that simplify lab to manufacturing correlation. DUV measurements are user configured and correlated via TMS software to known calibration standards.

## Technical Specifications

### ■ Measurements

<b>Source:</b>	DUV Lamp	<b>Repeatability:</b>	$\pm 0.2\text{\AA}$ ★★
<b>Spot Size:</b>	~8mm diameter	<b>Reproducibility:</b>	$\pm 0.25\text{\AA}$ or 1% (whichever is greater) ★★
<b>Number of Spots:</b>	Programmable (full sample to single test point)	<b>Spacial Filtering Frequency:</b>	(wavelength) Low Band: $.122$ to $.41\ \mu\text{m}^{-1}$ (2.41 to 8.20 $\mu\text{m}$ ) High Band: $.41$ to $1.43\ \mu\text{m}^{-1}$ (0.70 to 2.41 $\mu\text{m}$ ) Full Band: $.122$ to $1.43\ \mu\text{m}^{-1}$ (0.70 to 8.20 $\mu\text{m}$ ) Comp Band: Selectable from 0.2 to 150 $\mu\text{m}$
<b>Primary &amp; Secondary Results:</b>	RA or RMS (Rq) Microroughness P-V, RMS Slope, TIS, Diffuse Reflectance, Total Reflectance, Specular Reflectance		
<b>Speed:</b>	50 Measurements per 60 sec. ★		
<b>Range:</b>	From $1\text{\AA}$ up to $500\text{\AA}$ (RMS or RA)		
<b>Resolution:</b>	$0.01\text{\AA}$		

★ Varies with scan and user setup  
★★ Same sample, same machine

### ■ Rotary Stage

Repeatability:	$\pm 0.01^\circ$
Accuracy:	$\pm 0.05^\circ$

### ■ Linear Stage

Repeatability:	$\pm 0.0005$ inch ( $\pm 0.01$ mm)
Accuracy:	$\pm 0.0010$ inch ( $\pm 0.03$ mm)

### ■ Operating Environment

41°F (5°C) to 104°F (40°C)

### ■ Data Generation

ASCII Data Files (Detailed), SPC Data Files, Color plots with Scan Notes,

### ■ Computer

Pentium class Computer, available with optional

### ■ Sample Holders

Standard Disks: 65mm, 95mm  
Other sizes available

### ■ Materials

Glass, Glass/Ceramic, Composites, Aluminum

### ■ Installation

Electrical Requirements: 100-125 VAC – 60Hz  
Meets Class ten clean room requirements.

### ■ Shipping Weights

Computer:	70 lbs / 32 kg
TMS-2000DUV:	90 lbs / 41 kg
Total w/packing	160lbs / 72 kg

### ■ Dimensions

	Depth:	Width:	Height:
TMS-2000DUV	48.3cm (19")	59cm (23.25")	56.5 (22.25")
Computer:	33cm (13")	17.8cm (7")	38cm (14.96")



**SCHMITT  
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High Speed Full  
surface Scans

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